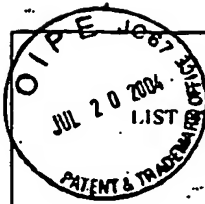
 <p>LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)</p>				ATTY. DOCKET NO:		APPLICATION SERIAL NO:		
				4717-8500		10/764, 289		
				APPLICANT:				
				Bruno GHYSELEN et al.				
FILING DATE:				GROUP:				
January 23, 2004				2812				
U.S. PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
Dh	AA	5,882,987	3/1999	Srikrishnan	438	458	—	
	AB	6,284,628 B1	9/2001	Kuwahara et al.	438	459	—	
	AC	6,306,729 B1	10/2001	Sakaguchi et al.	438	458	—	
	AD	6,326,279 B1	12/2001	Kakizaki et al.	438	406	—	
	AE	6,375,738	4/2002	Sato	117	89	—	
	AF	6,468,923 B1	12/2002	Yonehara et al.	438	761	—	
Dh	AG	2002/0072130 A1	6/2002	Cheng et al.	438	10	—	
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
Dh	AH	EP 0 955 671 A1	11/1999	Europe	/	/	X	
	AI	EP 1 039 513 A2	9/2000	Europe			X	
	AJ	EP 0 926 709 A2	6/1999	Europe			X	
	AK	EP 1006 567 A2	6/2000	Europe			X	
	AL	EP 0 849 788 A2		Europe			X	
	AM	WO 01/11930 A2	2/2001	PCT			X	
Dh	AN	WO 99/53539	10/1999	PCT			X	
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)								
Dh	AO	L. J. Huang et al, "SiGe-on-insulator prepared by wafer bonding and layer transfer for high-performance field-effect transistors", Applied Physics Letters, Vol. 78, No. 9, pp. 1267-1269 (2001)						
	AP	Q. Y. Tong et al "Extracts of "Semi-conductor on wafer bonding", Science and Technology, Interscience Technology, Wiley Interscience publication, Johnson Wiley & Sons, Inc.						
	AQ							
EXAMINER				DATE CONSIDERED				
Dh				4/2005				

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not

 REFERENCES CITED BY APPLICANT <i>(Use several sheets if necessary)</i>				ATTY. DOCKET NO.:		APPLICATION SERIAL NO.:	
				4717-8500		10/764,289	
				APPLICANT:			
				Bruno CHYSELEN et al.			
FILING DATE:				GROUP:			
January 23, 2004				2812			
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
Dh	AA	2001/0029072 A1	10/2001	Kuwahara et al.	438	151	—
	AB	2001/0003269 A1	6/2001	Wu et al.	117	94	—
	AC	2002/0068419 A1	6/2002	Sakaguchi et al.	438	458	—
	AD	2003/0124815 A1	7/2003	Henley et al.	438	460	—
	AE	2003/0159644 A1	8/2003	Yonehara et al.	117	8	—
Dh	AF	2004/0006311 A1	1/2004	Shchervinsky	604	164.01	—
	AG						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES NO
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
	AO						
	AP						
	AQ						
EXAMINER				DATE CONSIDERED			
Dh				4/2005			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							